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STATE OF THE PARTY		TO THE PARTY OF TH	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
APPLICATION NO. 09/981,889	FILING DATE	FIRST NAMED INVENTOR	492322002200	7319	
	10/19/2001	Nobuyuki Sekikawa	492322002200		
7590 10/23/2002 MORRISON & FOERSTER 1650 Tysons Blvd.			EXAMINER		
			VU, D	VU, DAVID	
Suite 300 McLean, VA 22102			ART UNIT	PAPER NUMBER	
McDean, VII	22.02		2818		
			14 0.0	*	

DATE MAILED: 10/23/2002

Please find below and/or attached an Office communication concerning this application or proceeding.

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<u>.</u>	Application No.	Applicant(s)	
	09/981,889	SEKIKAWA ET AL.	
Office Action Summary	Examiner	Art Unit	
	DAVID VU	2818	
The MAILING DATE of this communication ap	pears on the cover sh	eet with the correspondence address	
Paried for Panix			
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a rep. If NO period for reply is specified above, the maximum statutory period. Failure to reply within the set or extended period for reply will, by statul.  - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, by within the statutory minimu will apply and will expire SIX	may a reply be timely filed  m of thirty (30) days will be considered timely.  (6) MONTHS from the mailing date of this communication.	
Status  1)   Responsive to communication(s) filed on 05	September 2002		
	his action is non-fina	1.	
Za) This action is that L	wance except for forn	nal matters, prosecution as to the merits is	
3) Since this application is in condition for allow closed in accordance with the practice unde Disposition of Claims	er Ex parte Quayle, 19	935 C.D. 11, 453 O.G. 213.	
4) $\boxtimes$ Claim(s) <u>1-13</u> is/are pending in the application	on.		
4a) Of the above claim(s) <u>6-13</u> is/are withdra	wn from consideratio	n.	
5) Claim(s) is/are allowed.			
6)⊠ Claim(s) <u>1-5</u> is/are rejected.			
7) Claim(s) is/are objected to.			
8) Claim(s) are subject to restriction and	d/or election requirem	ent.	
Application Papers			
as The execition is objected to by the Exami	ner.	Company to the the Eveniner	
10) 54 The drawing(s) filed on 19 October 2001 is/a	ire: a)⊠ accepted or b	Objected to by the Examiner.	
that any objection to	the drawing(s) be neig	in abeyance. Sec or or it mostly	
11) The proposed drawing correction filed on	is: a)∐ approve	b) disapproved by the Examinor.	
If approved, corrected drawings are required in	reply to this Office acti	on.	
12) The oath or declaration is objected to by the	Examiner.		
a : 1/4			
13)⊠ Acknowledgment is made of a claim for fore	eign priority under 35	U.S.C. § 119(a)-(a) or (i).	
a)⊠ All b) Some * c) None of:			
Cortified copies of the priority docum	ents have been rece	ved.	
a wis at series of the priority docum	ents have been rece	ived in Application No	
3. Copies of the certified copies of the papplication from the International	priority documents ha I Bureau (PCT Rule 1 Jist of the certified co	7.2(a)). pies not received.	
* See the attached detailed Office action for a 14) Acknowledgment is made of a claim for dom	nestic priority under 3	5 U.S.C. § 119(e) (to a provisional applicatio	າn).
l su s 'malamanage	S PROVICIONAL ADDITICATI	OII Has been received:	
a)  The translation of the foreign language  15)  Acknowledgment is made of a claim for don	nestic priority under 3	5 U.S.C. §§ 120 and/or 121.	
Attachment(s)	4) 🗆	Interview Summary (PTO-413) Paper No(s).	
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statement(s) (PTO-1449) Paper No.</li> </ol>	5)	Notice of Informal Patent Application (PTO-152)	

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## DETAILED ACTION

## Election/Restriction

Application's election without traverse of Group I (Claims 1-5) in Paper No.5 is 1. acknowledge.

## Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- Claims 1 and 3-4 are rejected under 35 U.S.C. 102(b) as being anticipated by Koga (US 2. 5,936,265).

Koga, in related text (Col. 17, Line 57-Col. 18, Line 22 and Col. 24, Lines 16-23) and figures (Figs. 23a-B) disclose a semiconductor device comprising: a resistance layer706 formed on a semiconductor substrate of a first conductivity type and of a second conductivity type, one end of said resistance layer 706 being adapted to have a first voltage (Vss) applied thereto, another end of said resistance layer 706 being adapted to have a second voltage (Vdd) applied thereto; an oxide film 704 formed on the resistance layer706; and a resistance bias electrode layer comprising a silicon layer 705 formed on the oxide film 704; wherein the device is configured so that voltage dependence of a resistance of the resistance layer is reduced by adjusting the voltage applied to the resistance bias electrode layer.

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3. Claims 1-4 are rejected under 35 U.S.C. 102(b) as being anticipated by Choi et al. (US 5,686,754).

Choi et al., in related text (Col. 2, Line 53-Col. 3, Line 51 and Col. 4, Lines 8-55) and figures (Figs. 1-3) disclose a semiconductor device comprising: a resistance layer formed on a semiconductor substrate 20 of a first conductivity type and of a second conductivity type, one end of said resistance layer being adapted to have a first voltage (600V) applied thereto, another end of said resistance layer being adapted to have a second voltage (600V) applied thereto; an oxide film 80 formed on the resistance layer; and a resistance bias electrode layer comprising a silicon layer 7/7a formed on the oxide film 80; wherein the device is configured so that voltage dependence of a resistance of the resistance layer is reduced by adjusting the voltage applied to the resistance bias electrode layer.

# Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claim 5 is rejected under 35 U.S.C. 103(a) as being unpatentable over Choi et al.,(US 5,686,754).

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Choi et al., disclose all claimed subject matter, but fails to expressly disclose the ratio of the voltage applied to the pair of the electrode pad layers to the voltage applied to the resistance bias layer is 0.5-0.6.

Choi, in related text, (Col. 2, Lines. 53-65) disclose the ratio of the voltage applied to the pair of the electrode pad layers to the voltage applied to a resistance bias electrode layer is 0.98 (600V/615V). It would have been obvious to one with ordinary skill in the art at the time of the invention to judiciously adjust and control the ratio of the voltage applied to the pair of the electrode pad layers to the voltage applied to the resistance bias layer through routine experimentation and optimization to achieve optimum benefits (see MPEP 2144.05) and it would not yield any unexpected results.

#### Conclusion

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to David Vu whose telephone number is (703) 305-0391. The examiner can normally be reached on Monday-Friday from 8:00am to 5:00pm.

If attempt to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms., can be reached on (703) 308-4910.

DV

David Vu

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PRIMARY EXAMINER